

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 7,348,595 B2
APPLICATION NO. : 10/828492
DATED : March 25, 2008
INVENTOR(S) : Sadami Takeoka et al.

Page 1 of 1

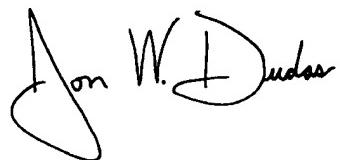
It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

On the Title page, in Item "(54)" and Column 1, lines 1-5, the title of the application, change "SEMICONDUCTOR WIRING SUBSTRATE, SEMICONDUCTOR DEVICE, METHOD FOR TESTING SEMICONDUCTOR DEVICE, AND METHOD FOR MOUNTING SEMICONDUCTOR DEVICE" to --SEMICONDUCTOR DEVICE AND METHOD FOR TESTING SEMICONDUCTOR DEVICE--;

In Item "(56) References Cited", change "2003/0008795 A1 01/2003 Asayama et al." to --2003/0006795 A1 01/2003 Asayama et al.--; and change "2003/0032283 A1 02/2003 Nagao et al." to --2003/0032263 A1 02/2003 Nagao et al.--.

This certificate supersedes the Certificate of Correction issued October 7, 2008.

Signed and Sealed this
Twenty-first Day of October, 2008



JON W. DUDAS
Director of the United States Patent and Trademark Office